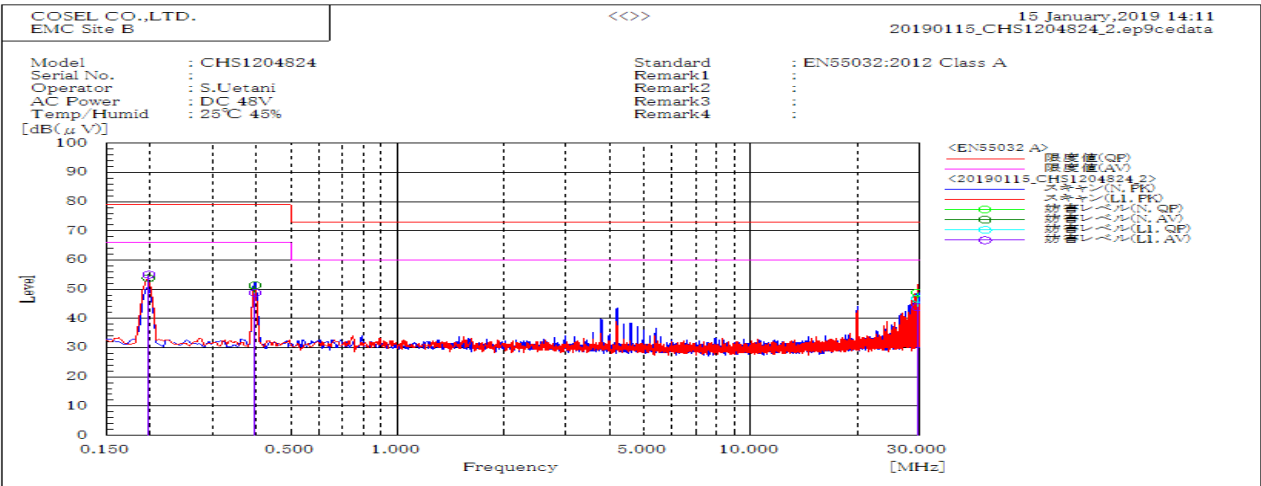
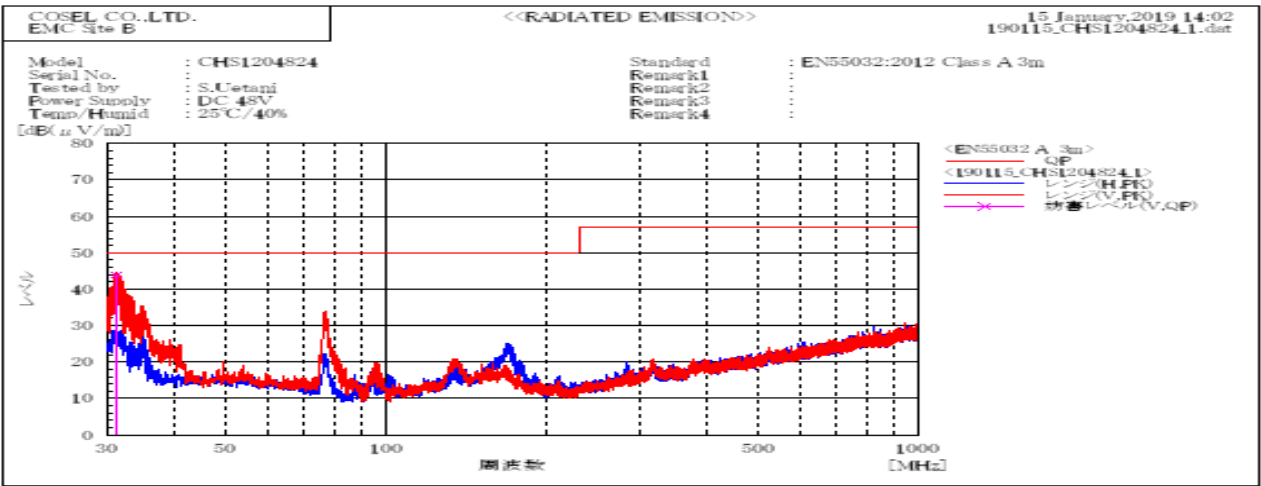


DATA SHEET		Date	05-Mar-19
Model	CHS1204824	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Uetani



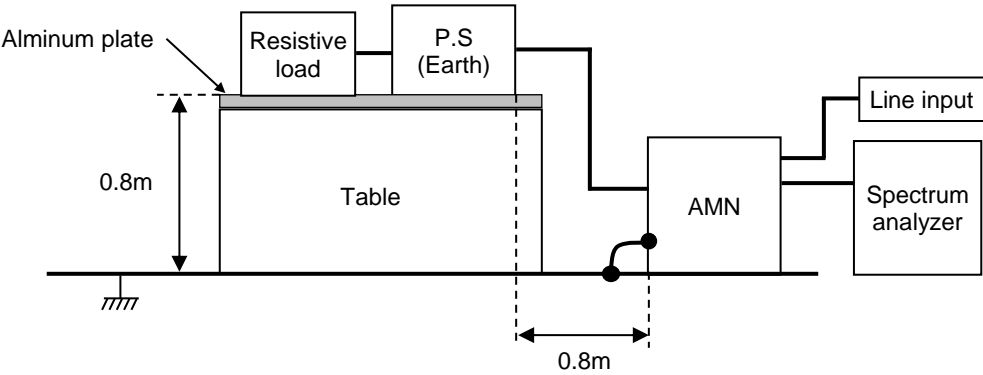
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.198	L1	55	55	79	66	24	11	Pass	
0.396	L1	48.8	48.7	79	66	30.2	17.3	Pass	
29.665	L1	46.9	43.8	73	60	26.1	16.2	Pass	
0.198	N	53.8	53.8	79	66	25.2	12.2	Pass	
0.396	N	51.3	51.3	79	66	27.7	14.7	Pass	
29.664	N	48.9	46.8	73	60	24.1	13.2	Pass	



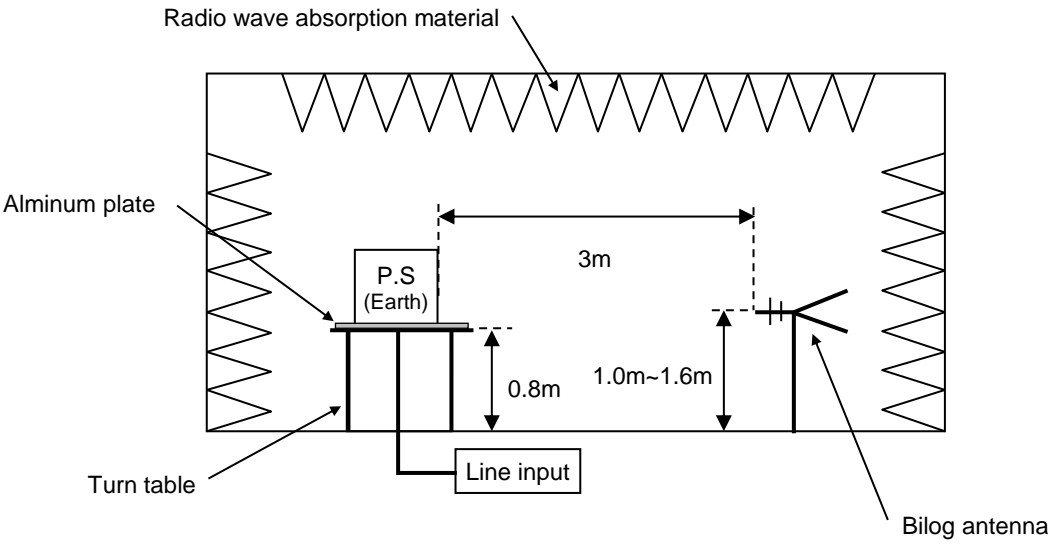
Frequency MHz	Polarization	Stability	Level dB(μV/m)	Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
31.354	V	Stable	43.9	50	6.1	Pass	103.3	337	

DATA SHEET		Date	05-Mar-19
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Uetani

1. Line conduction



2. Radiated emission

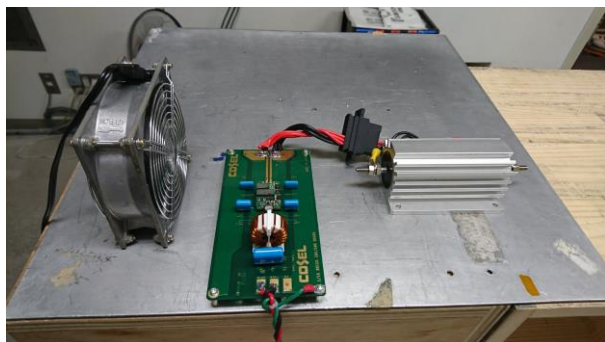


## Conditions

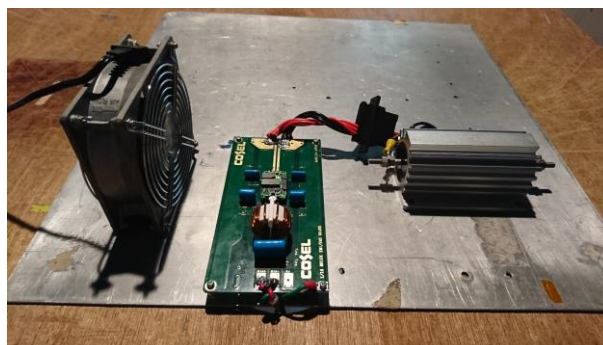
Test : EMI  
Model Name : CHS12048□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

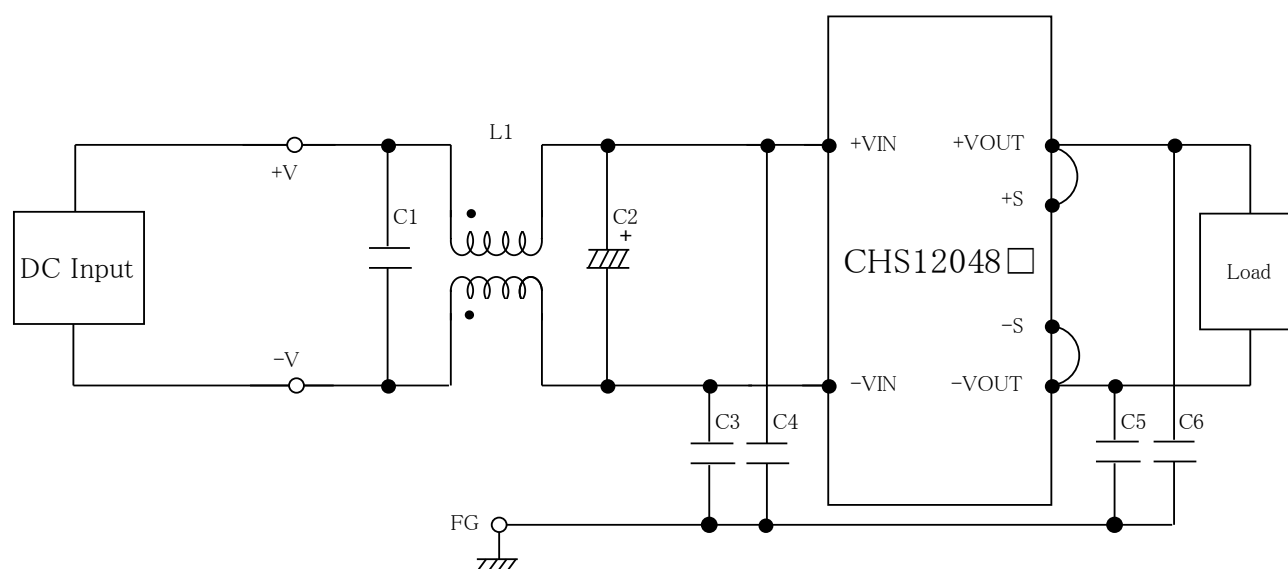


Fig.1 Testing circuitry

L1 : 1mH SC-05-10J (TOKIN)  
C1 : 250V 2.2  $\mu$ F FPD22E225J4 (NITSUKO)  
C2 : 100V 47  $\mu$ F PWseries (nichicon)  
C3,C4 : 630V 0.068  $\mu$ F FPD22J683J4 (NITSUKO)  
C5,C6 : 630V 0.033  $\mu$ F FPD22J333J4 (NITSUKO)